

FLT703 LD-TO
Mass Production Tester



Description

1. This system is suitable for TO-CAN LD testing.
2. 64pcs of LD can place on one testing board.
The testing board is compatible with LD ACC burn-in system. Thus can reduce plug-play procedure.
3. Able to sweepingly testing or single LD testing.
4. Pins of LD can define by software & users do not need to adjust position of LD.

Features

1. L-I-V Curve Tracer
2. ACC Mode (Auto Current Controller)
3. APC Mode (Auto Power Controller)
4. Dark Current measurement
5. Optical Power measurement
6. User Define Pin Position
7. L-I-V Curve Display

Parameters

Parameter	Unit	Symbol
Operator Current	mA	Iop
Operator Voltage	V	Vop
Series Resistance	ohm	Rs
Threshold Current	mA	Ith
Slope Efficiency	W/A	SE
Sensitivity of Monitor PD	uA/mW	PD-S
Forward Power	mW	Pf
Forward Voltage	V	Vf
Monitor PD Current of Pop	uA	Im-Pop
Monitor PD Current of Pf	uA	Im-Pf
Power of Kink	uW	Pkink
Current of Kink	mA	Ikink

Optical Power Sensor Responsivity

Wavelength	850nm		1300nm		1550nm	
	Min.	Typ.	Min.	Typ.	Min.	Typ.
(Ge Detector)	0.20	0.26	0.60	0.70	0.75	0.85

Ge Detector 響應規格表 (Detect Range : 800~1600nm)

Wavelength	780nm		850nm		980nm	
	Min.	Typ.	Min.	Typ.	Min.	Typ.
PIN10DP	0.52	0.57	0.58	0.60	0.60	0.62

Si-PIN Detector 響應規格表 (Detect Range : 450~1000nm)

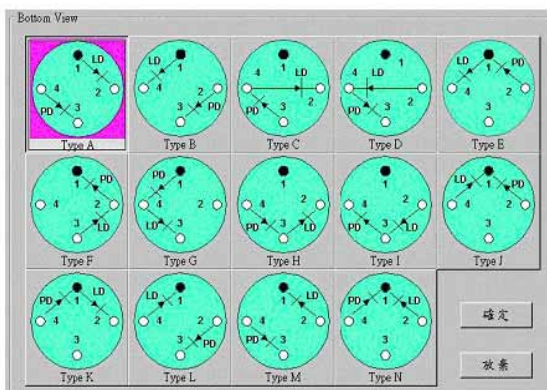


Fig.1 User define pin position

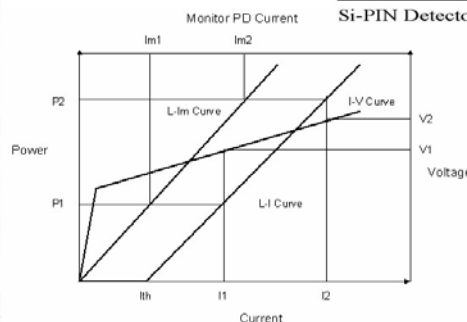


Fig.2 L-I-V curve display

Order Information

FLT-703	LD -TO Mass Production Tester
FLT-703-02	Keithly2400



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